



ZVEI Matrix (Extract):

ID	Type of change	Mn	Ter	Appl: B: Bore C: Comp P: Part M: Mater	Line level (can be)	AEC-C
AMT						
SEM-AM-01	Any change with impact on agreed upon contractual agreement	P	P	**	-	
DATA SHEET						
SEM-DS-02	Correction of datasheet errors	I	P	A	-	
DESIGN						
PROCESS - WAFER PRODUCTION						
SEM-PW-05	Change of gate material / dielectric	P	P	A	-	
SEM-PW-08	New / change of passivation or die coating (without bare die)	P	P	C	-	
SEM-PW-13	Move of all or part of wafer fab to a different location / site / sub-contractor	P	P	A	*	
BARE DIE						
PROCESS - ASSEMBLY						
SEM-PA-04	Change of lead frame finishing material / area (internal)	P	P	C	-	
SEM-PA-07	Die attach material	P	P	C	-	
SEM-PA-18	Move of all or part of assembly to a different location / site / sub-contractor.	P	P	C	*	
PACKING / SHIPPING						
EQUIPMENT						
TEST FLOW						
Q-GATE						

Attachments:

Attached IBEE Test Report:

To access file attachment on the pdf copy of PCN, please be guided by the steps below:

1. Download pdf copy of the PCN to your computer.
2. Open the downloaded pdf copy of the PCN.
3. Click on the paper clip icon available on the menu provided in the left/bottom portion of the screen to reveal the Attachment field
4. Then click on the attached file/s.

List of Affected Standard Parts:

FAB2 Orderable Part Number	Gresham Orderable Part Number	Qualification Vehicle
NCV7381DP0R2G	NCV7381ADP0R2G	ORAYA